# onsemi

## Silicon Carbide (SiC) MOSFET – 40 mohm, 1200 V, M1, D2PAK-7

## NTBG040N120SC1

#### Features

- Typ.  $R_{DS(on)} = 40 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>G(tot)</sub> = 106 nC)
- Low Effective Output Capacitance (Typ. Coss = 139 pF)
- 100% Avalanche Tested
- $T_J = 175^{\circ}C$
- This Device is Halide Free and RoHS Compliant with exemption 7a, Pb–Free 2LI (on second level interconnection)

#### **Typical Applications**

- UPS
- DC-DC Converter
- Boost Inverter

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	1200	V
Gate-to-Source Voltag	je		V <sub>GS</sub>	+25/-15	V
Recommended Operat of Gate-Source Voltag		T <sub>C</sub> < 175°C	V <sub>GSop</sub>	+20/-5	V
Continuous Drain Current (Note 1)	Steady State	$T_C = 25^{\circ}C$	۱ <sub>D</sub>	60	A
Power Dissipation (Note 1)			P <sub>D</sub>	357	W
Continuous Drain Current (Note 1)	Steady State	T <sub>C</sub> = 100°C	۱ <sub>D</sub>	43	A
Power Dissipation (Note 1)			PD	178	W
Pulsed Drain Current (Note 2) $T_A = 25^{\circ}C$			I <sub>DM</sub>	240	А
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	–55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	36	А
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L</sub> = 34 A <sub>pk</sub> , L = 1 mH) (Note 3)			E <sub>AS</sub>	578	mJ
Maximum Lead Temperature for Soldering, 1/8" from Case for 10 Seconds			ΤL	300	°C

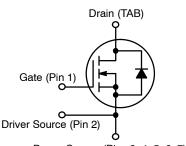
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Repetitive rating, limited by max junction temperature.

3. E<sub>AS</sub> of 578 mJ is based on starting  $T_J$  = 25°C; L = 1 mH, I<sub>AS</sub> = 34 A, V<sub>DD</sub> = 120 V, V<sub>GS</sub> = 18 V.

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
1200 V	56 mΩ @ 20 V	60 A	



Power Source (Pins 3, 4, 5, 6, 7)

#### **N-CHANNEL MOSFET**



D2PAK-7L CASE 418BJ

#### MARKING DIAGRAM



= Assembly Location

= Year

A Y

- WW = Work Week
- ZZ = Lot Traceability

NTBG040120SC1 = Specific Device Code

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTBG040N120SC1	D2PAK-7L	800 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, <u>BRD8011/D</u>.

#### Table 1. THERMAL CHARACTERISTICS

Parameter	Symbol	Мах	Unit
Thermal Resistance Junction-to-Case (Note 1)	$R_{ extsf{ heta}JC}$	0.42	°C/W
Thermal Resistance Junction-to-Ambient (Note 1)	$R_{\theta JA}$	40	°C/W

#### Table 2. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = $25^{\circ}C$ unless otherwise stated)

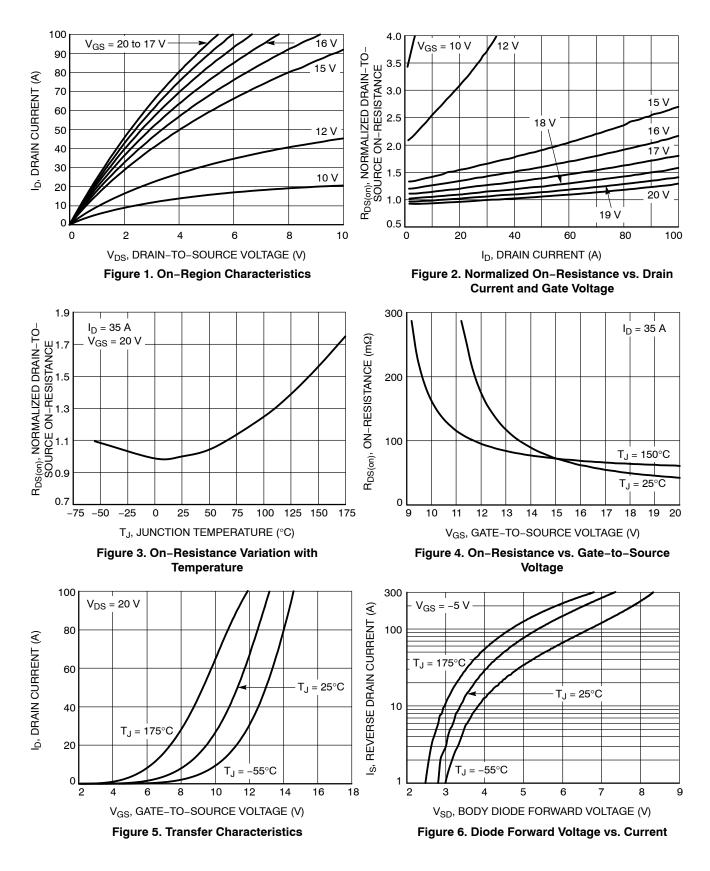
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	-			-	-	-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 V, I_{D} = 1 mA$	1200			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	$I_D = 1$ mA, refer to $25^{\circ}C$		0.45		V/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ , $T_J = 25^{\circ}C$			100	μA
		$V_{\rm DS} = 1200 \text{ V}$ $T_{\rm J} = 175^{\circ}\text{C}$	;		1	mA
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = +25/-15 V, V <sub>DS</sub> = 0 V			±1	μΑ
ON CHARACTERISTICS (Note 2)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 10 \text{ mA}$	1.8	3	4.3	V
Recommended Gate Voltage	V <sub>GOP</sub>		-5		+20	V
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 20 V, I <sub>D</sub> = 35 A, T <sub>J</sub> = 2	5°C	40	56	mΩ
		$V_{GS}$ = 20 V, I <sub>D</sub> = 35 A, T <sub>J</sub> = 1	75°C	71	100	mΩ
Forward Transconductance	<b>9</b> FS	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 35 A		20		S
CHARGES, CAPACITANCES & GATE RES	ISTANCE		•			
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz,		1789		pF
Output Capacitance	C <sub>OSS</sub>	V <sub>DS</sub> = 800 V		139		
Reverse Transfer Capacitance	C <sub>RSS</sub>			12.5		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = -5/20 \text{ V}, \text{ V}_{DS} = 600 \text{ V},$		106		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	I <sub>D</sub> = 47 A		18		
Gate-to-Source Charge	Q <sub>GS</sub>			34		
Gate-to-Drain Charge	Q <sub>GD</sub>			26		
Gate-Resistance	R <sub>G</sub>	f = 1 MHz		2		Ω
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t <sub>d(ON)</sub>	V <sub>GS</sub> = -5/20 V, V <sub>DS</sub> = 800 V,		17	30	ns
Rise Time	t <sub>r</sub>	$I_D = 47 \text{ A}, \text{ R}_G = 4.7 \Omega,$ Inductive Load		20	36	
Turn-Off Delay Time	t <sub>d(OFF)</sub>			30	48	
Fall Time	t <sub>f</sub>			9	18	
Turn–On Switching Loss	E <sub>ON</sub>			366		μJ
Turn–Off Switching Loss	E <sub>OFF</sub>			200		
Total Switching Loss	E <sub>TOT</sub>			566		
DRAIN-SOURCE DIODE CHARACTERIST						<u>n</u>
Continuous Drain-Source Diode Forward Current	I <sub>SD</sub>	$V_{GS}$ = -5 V, $T_J$ = 25°C			36	A
Pulsed Drain-Source Diode Forward Current (Note 2)	I <sub>SDM</sub>	$V_{GS}$ = -5 V, $T_J$ = 25°C			240	A
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS}$ = -5 V, I <sub>SD</sub> = 17.5 A, T <sub>J</sub> 25°C	=	3.7		V

#### Table 2. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = $25^{\circ}$ C unless otherwise stated) (continued)

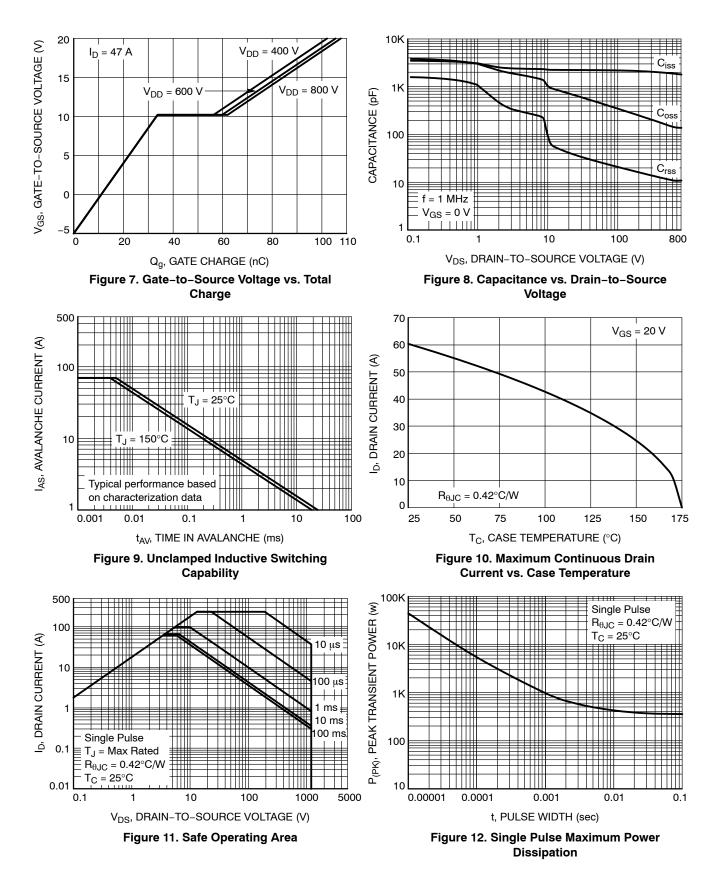
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS								
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = -5/20 \text{ V}, I_{SD} = 47 \text{ A},$		24		ns		
Reverse Recovery Charge	Q <sub>RR</sub>	dl <sub>S</sub> /dt = 1000 A/µs		124.8		nC		
Reverse Recovery Energy	E <sub>REC</sub>			8.4		μJ		
Peak Reverse Recovery Current	I <sub>RRM</sub>	]		10.4		А		
Charge Time	Та	]		12.4		ns		
Discharge Time	Tb	1		11.6		ns		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**



#### TYPICAL CHARACTERISTICS (continued)



#### TYPICAL CHARACTERISTICS (continued)

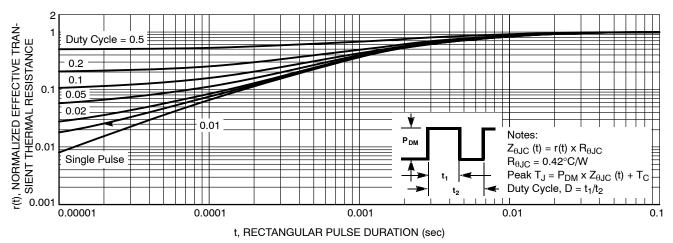
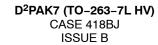


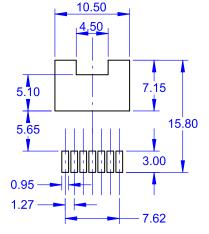
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

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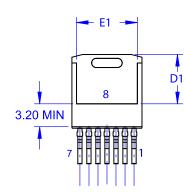




Α F L1 D b2 е h  $\oplus$ aaa B A M



LAND PATTERN RECOMMENDATION



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GENERIC **MARKING DIAGRAM\*** 

XXXXXXXXX AYWWG
0

XXXX = Specific Device Code А = Assembly Location Y = Year

- WW = Work Week
- G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

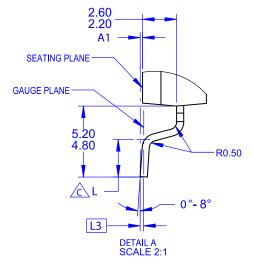
B	A
c2 —	
•	
H	
	A

NOTES:

A. PACKAGE CONFORMS TO JEDEC TO-263 VARIATION CB EXCEPT WHERE NOTED. B. ALL DIMENSIONS ARE IN MILLIMETERS.

C OUT OF JEDEC STANDARD VALUE. D. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009. E. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.

DIM	MILLIMETERS				
	MIN	NOM	MAX		
Α	4.30	4.50	4.70		
A1	0.00	0.10	0.20		
b2	0.60	0.70	0.80		
b	0.51	0.60	0.70		
С	0.40	0.50	0.60		
c2	1.20	1.30	1.40		
D	9.00	9.20	9.40		
D1	6.15	6.80	7.15		
E	9.70	9.90	10.20		
E1	7.15	7.65	8.15		
е	~	1.27	~		
Н	15.10	15.40	15.70		
L	2.44	2.64	2.84		
L1	1.00	1.20	1.40		
L3	~	0.25	~		
aaa	~	~	0.25		



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